

Cp E 432: Testing of Computing Systems **Electrical Engineering**

Physical defects from semiconductor manufacture, fault modeling and simulation, fault activation and detection in digital systems, digital test pattern synthesis, test coverage, test compaction, online/offline/BIST testing concepts, design-for-test, design-for- manufacture, system testability and diagnosability.

Prerequisites

- El E 351: Electronics Circuits | \$target.descriptions.MinimumGrade\$
- El E 385: Advanced Digital Systems \$target.descriptions.MinimumGrade\$
- El E 386: Advanced Digital Systems Laboratory \$target.descriptions.MinimumGrade\$

Instruction Type(s)

• Lecture: Lecture for Cp E 432

Subject Areas

• Computer Engineering, General

Related Areas

Computer Hardware Engineering

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